

Optimizing Reflow Profiling in Lead-free SMT Assembly

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Outline

- Reflow phases
- Max slope vs. ramp rate
- Factors affecting reflow process window
- Solder defects
- Conclusion

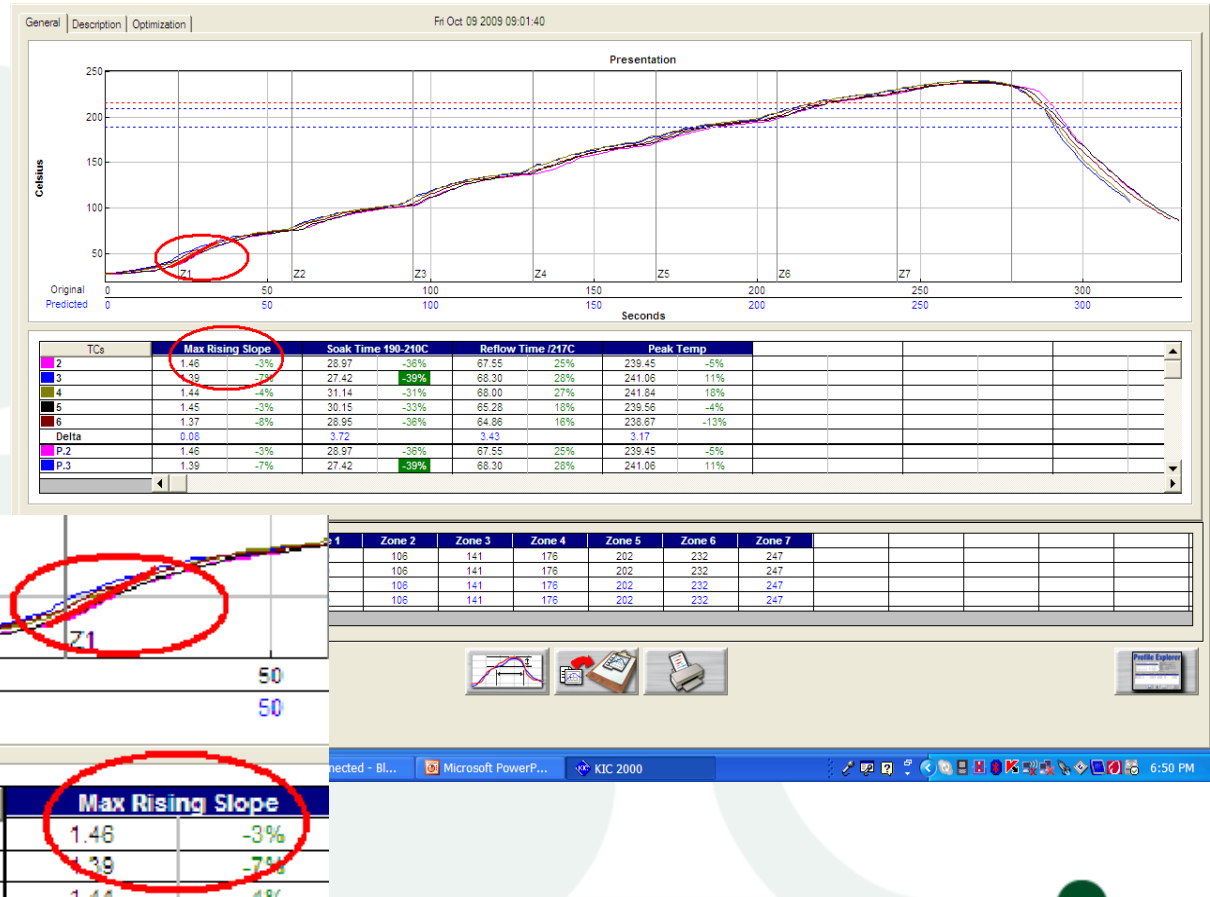


Reflow Phases

- **Preheat**
 - Minimize thermal shock
 - Drive off volatiles
 - Ramp rate
- **Pre-reflow**
 - Flux activation/oxide removal
 - Void minimization
- **Reflow**
 - Intermetallic formation
 - Peak
 - TAL
- **Cooling**
 - Grain structure
 - Minimize CTE

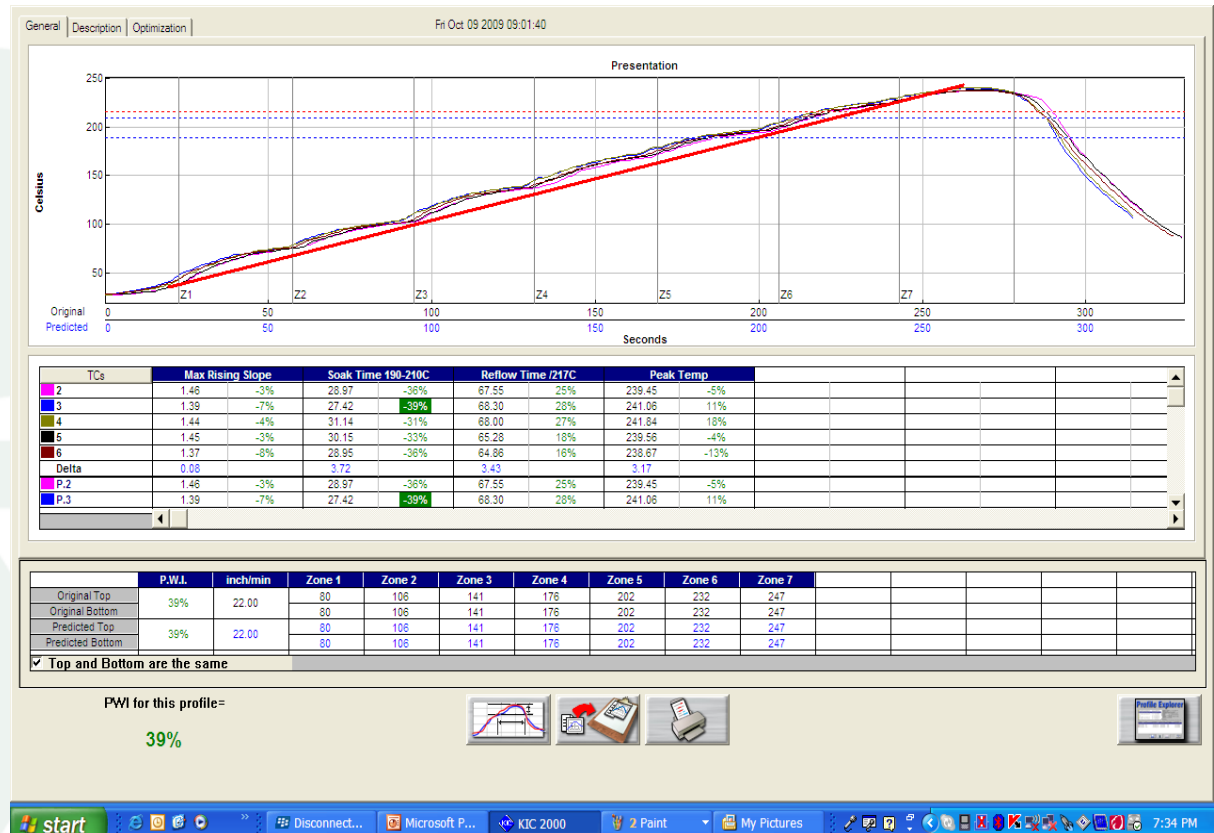
Preheat Ramp Rate

- Max (+) Slope
1.46°C/s
- Ambient to peak
4min 40s (280s)
- $1.46^{\circ}\text{C/s} \times 280\text{s} = 408.8^{\circ}\text{C}$ increase from ambient to peak
- 25°C (ambient) + $408.8^{\circ}\text{C} = 433.8^{\circ}\text{C}$ peak



Preheat Ramp Rate

- True ramp rate or slope is from ambient to peak (RTP profile)
- Ramp rate considerations for soak profile
- Ramp rate = $\Delta\text{Temp} / \Delta\text{time}$
- $214^{\circ}\text{C} / 280\text{s} = 0.76^{\circ}\text{C/s}$



Factors Affecting Reflow Process Window

- **Water soluble vs. RMA/no-clean**
- **Powder type**
- **Board size**
- **Component density/diversity**

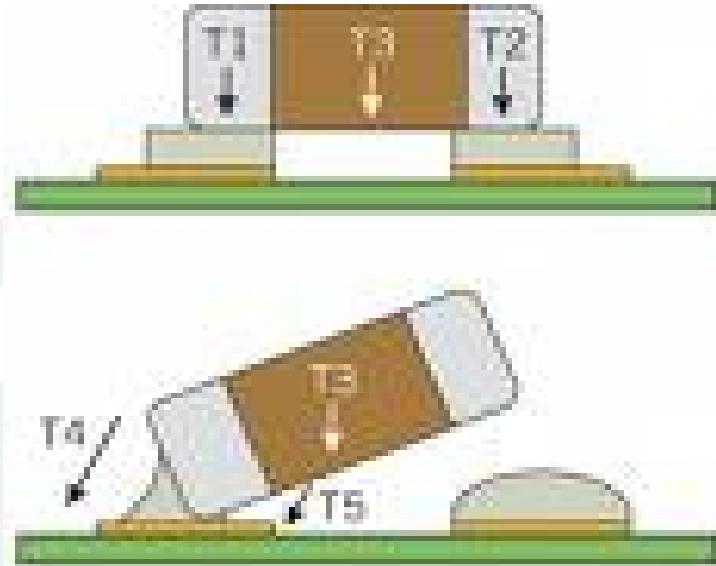


Solder Defects

- **Tombstoning**
- **Solder Balling/Beading**
- **Voiding**
- **Graping**
- **Head-in-Pillow (HIP)**

Tombstoning

- **Unbalanced wetting forces – leadless component**
 - Weight of chip
 - Surface tension under chip
 - Surface tension side of chip



Tombstoning

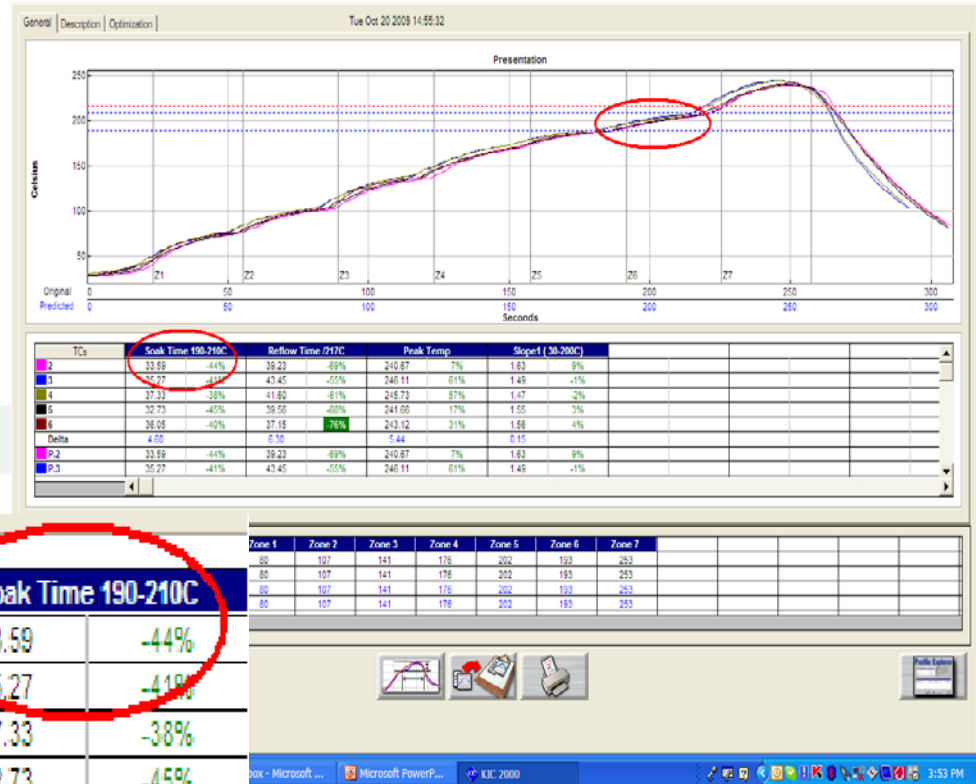
- **Profile recommendations**

- Minimize thermal gradient before reflow

- Slow ramp rate (belt speed)

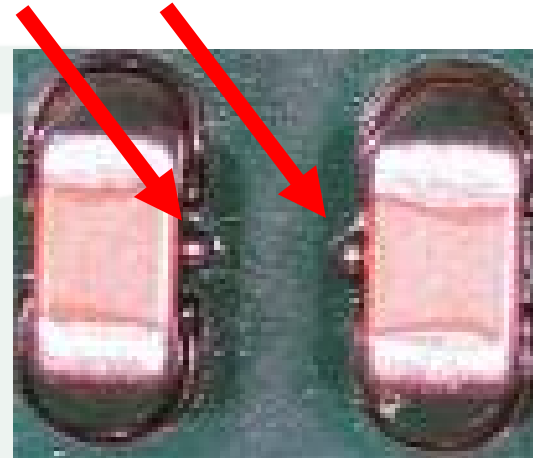
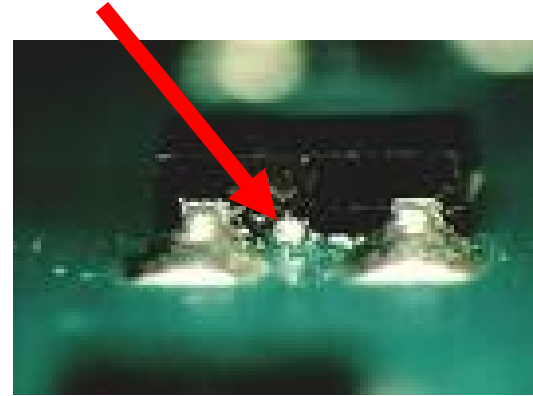
- “Shoulder” soak

- Effect of nitrogen



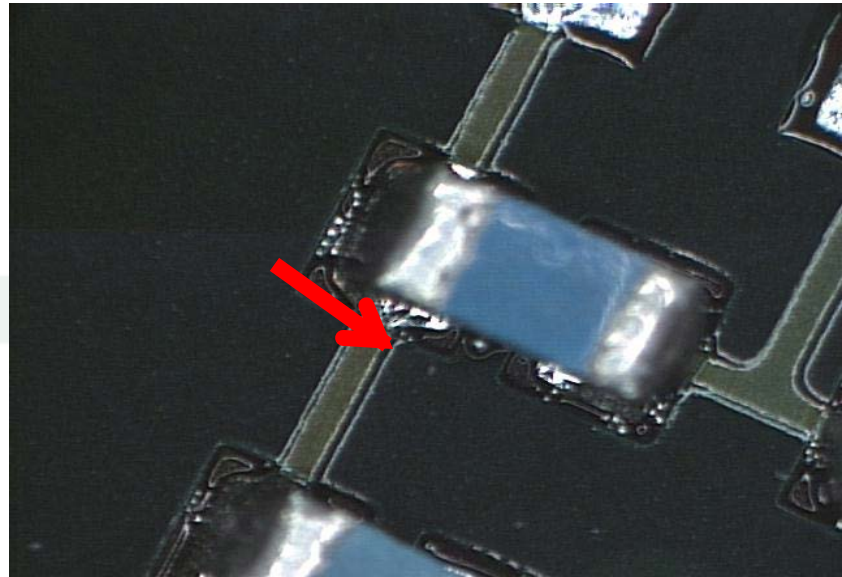
Solder Beading

- Isolated paste aggregates
- Low stand-off components
- Pad design



Solder Balling

- **Small particles isolated from solder joint**
 - Origin
 - Flux spattering
 - Flux slump
 - Solder mask
 - Oxidation



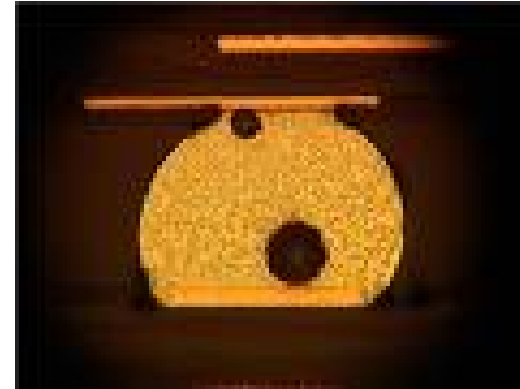
Solder Beading/Balling

- **Profile recommendations**
 - Ramp to peak profile
 - Ramp rate (ambient to peak) 1-1.5C/s



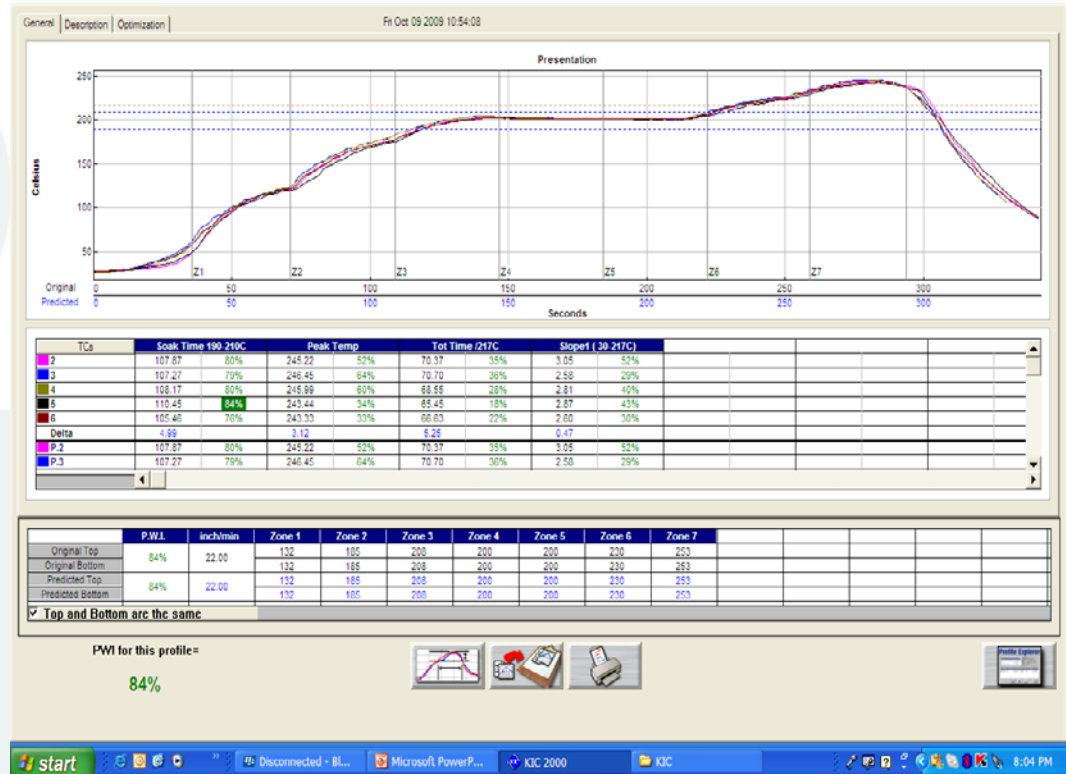
Voiding

- **Components such as BGA, LGA, SGA, QFN, flip-chip**
- **Out-gassing entrapped flux**
- **Wetting**
- **Particle size/ powder type**



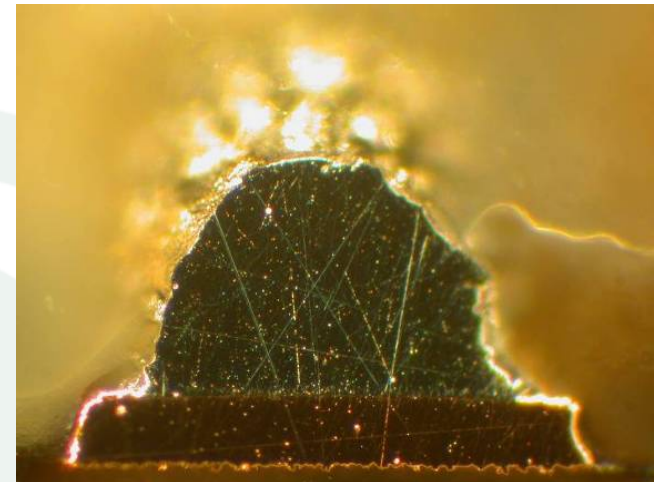
Voiding

- **Profile recommendations**
 - Raising peak temperature
 - Lowering peak temperature
 - Soak
 - Mixed alloy



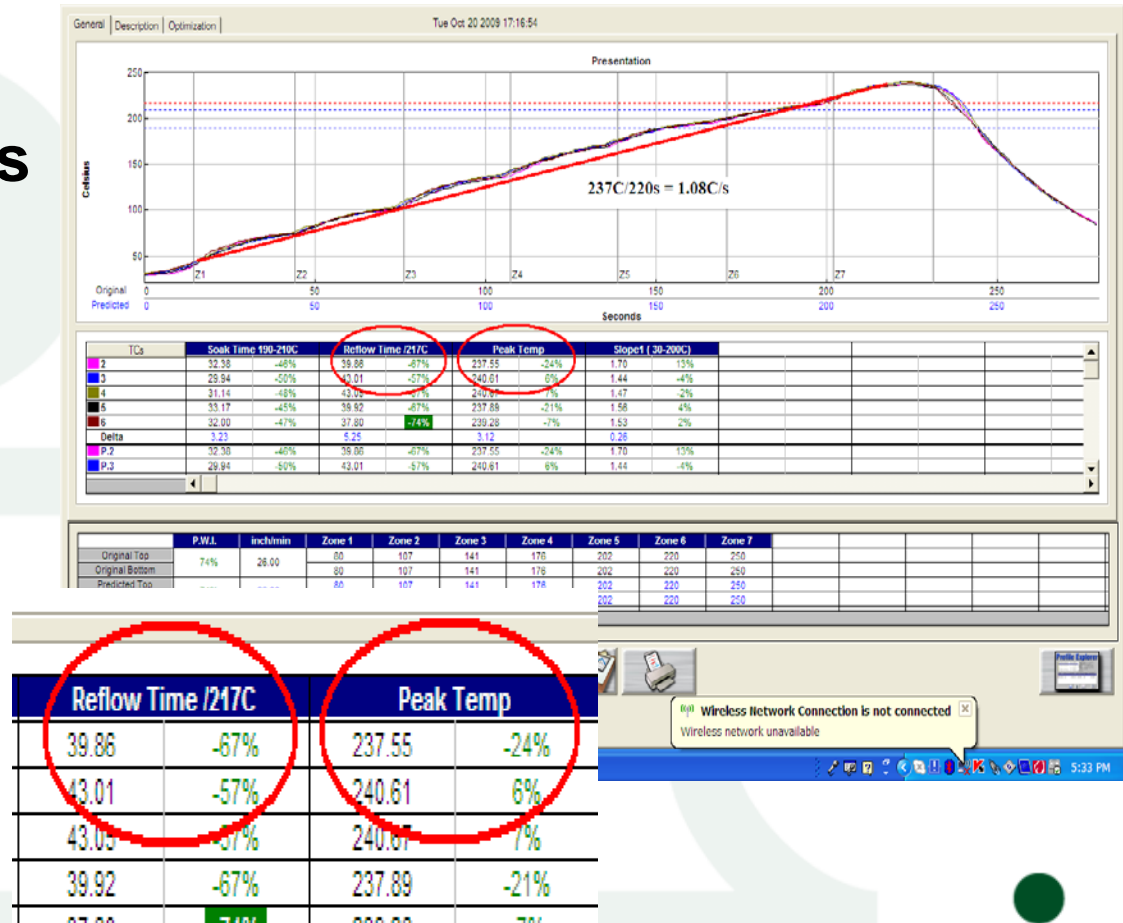
Graping

- **Small print deposits translate to large surface-area-to flux ratio**
- **Fluxing capacity diminished**
- **Flux “run-away”**
- **Oxidized solder particles**
- **Mask defined vs. non-solder mask defined**
- **Resistors more prone than capacitors**



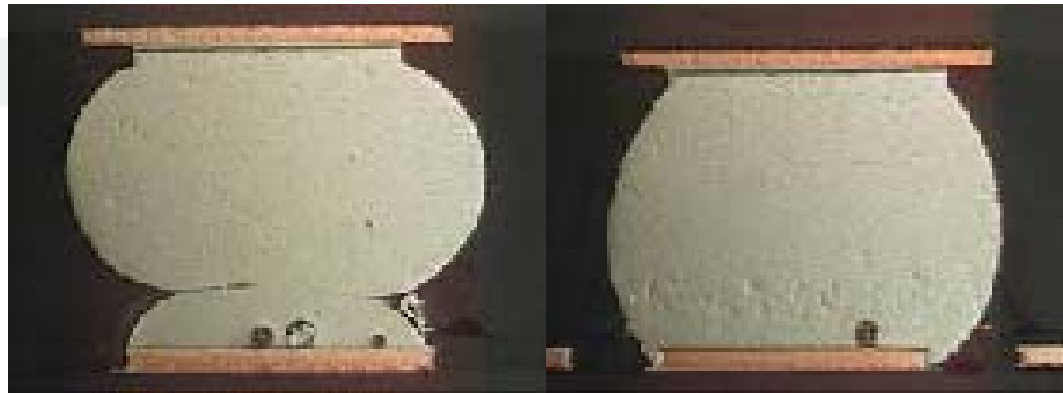
Graping

- **Profile recommendations**
 - Increase ramp rate ($\geq 1^\circ\text{C/s}$)
 - Lower peak temperature
 - Shorter time above liquidus



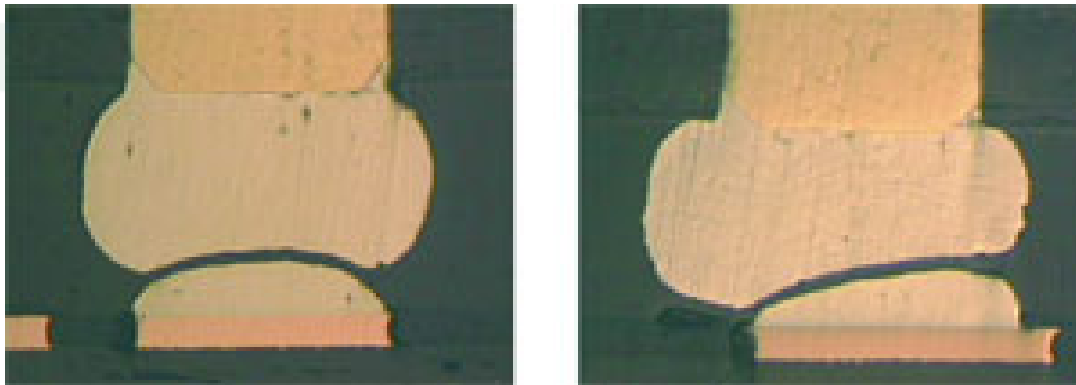
Head-in-Pillow

- **Component warpage**
- **Co-planarity**
- **Poor transfer efficiency/registration**
- **Placement**



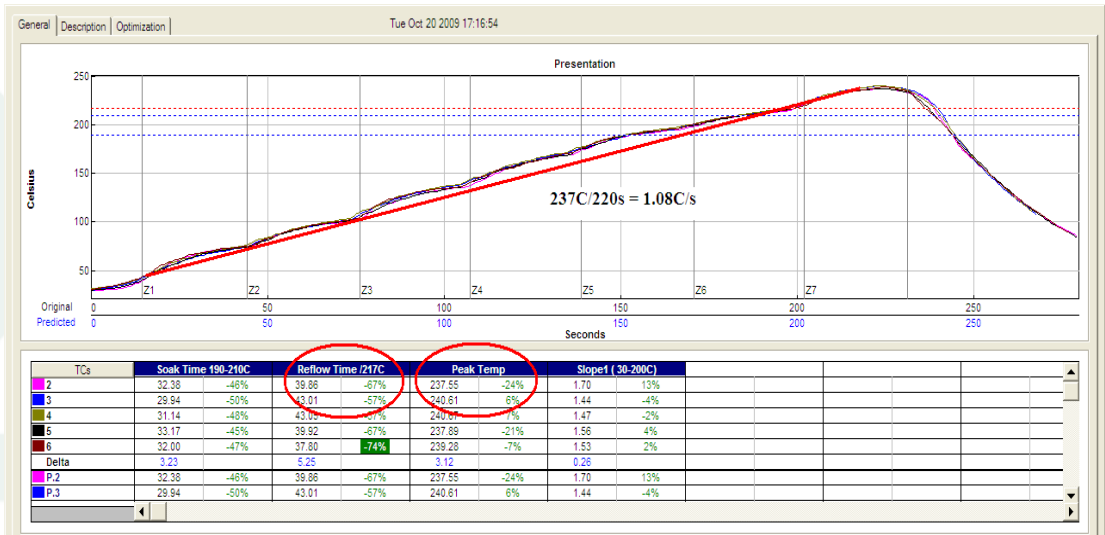
Head-in-Pillow

- **Sphere oxidation**
- **Contaminants**
- **Flux exhaustion**



Head-in-Pillow

- **Avoid excessive heat exposure**
 - Total time in oven (increase ramp rate)
 - RTP vs. Soak
 - Lower peak temperature
 - Shorter TAL
 - Inert atmosphere



Conclusion

- **Lead-free challenges on solder paste**
- **Understanding reflow profile**
- **Optimizing the reflow process**

